

Docket No.: 217075US6YA PCT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION: Joseph T. VERDEYEN et al.

SERIAL NO.: 10/031,570

GAU: 2133

FILED: March 28, 2002

EXAMINER: KERVEROS, JAMES C.

FOR: ELECTRON DENSITY MEASUREMENT AND PLASMA PROCESS CONTROL SYSTEM
USING CHANGES IN THE RESONANT FREQUENCY OF AN OPEN RESONATOR
CONTAINING THE PLASMA

LETTER SUBMITTING REPLACEMENT DRAWING SHEET(S)

COMMISSIONER FOR PATENTS
Alexandria, VA 22313

SIR:

Responsive to the below indicated communication, the following drawing sheets are submitted herewith:

☒ 1 Replacement Drawing Sheets

☐ _____ New Drawing Sheets

☒ Official Action dated June 2, 2004

☐ Notice of Allowance/Issue Fee dated _____

☐ Other dated _____

The changes and/or modifications made include the following:

The designator terms " f_{\max} ," " f_{\min} ," " f_{final} ," and " f_{open} " are now printed in proper character size.

Respectfully Submitted,

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